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Examiner

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Applicant(s)/Patent Under Reexamination

LEE, JEONG SIK

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ORIGINAL**CLASS** **SUBCLASS (ONE SUBCLASS PER BLOCK)**

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CROSS REFERENCE(S)**INTERNATIONAL CLASSIFICATION****NON-CLAIMED**

Richale L. Haney (Assistant Examiner)	1/3/2007 (Date)	GARY L. WELCH SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700	Total Claims Allowed: 19
Legal Instruments Examiner	1/8/07 (Date)	1 / 8 / 07 (Primary Examiner)	O.G. Print Figure 1 2